

Notice of References Cited	Application/Control No. 10/570,594		Applicant(s)/Patent Under Reexamination TAKATOH ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Juarrenz et al. (april 1996) J. of Microscopy vol. 182, pt. 1, pp. 46-49 (cited in IDS provided by applicant)
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